

SEMICONDUCTOR INTEGRATED CIRCUIT AND  
METHOD OF TESTING SEMICONDUCTOR INTEGRATED CIRCUIT

BACKGROUND OF THE INVENTION

5       The present invention relates to a technique of testing a ROM that is built in a semiconductor integrated circuit.

FIG. 4 illustrates a configuration for a known ROM-built-in semiconductor integrated circuit with a tester. The circuit shown in FIG. 4 includes selectors 61 and 62 connected to  
10 the input terminals of a ROM 51 and another selector 63 connected to the output terminal of the ROM 51. The tester is made up of these three selectors 61, 62 and 63. When a test signal **TEST** received at an input terminal **S** is in logical one state (which will be herein referred to as "at H-level"), each  
15 of these selectors 61, 62 and 63 selects and outputs a signal received at another input terminal **A**.

In testing the ROM 51, the test signal **TEST** is asserted to H-level and supplied to the respective input terminals **S** of the selectors 61, 62 and 63. Then, input data received at  
20 external input terminals **IN1** and **IN2** are delivered as address and read inputs **ADD** and **READ** to the ROM 51 through the selectors 61 and 62, respectively. Subsequently, the output data **DO** of the ROM 51 is delivered through an external output terminal **OUT** by way of the selector 63. In this manner, according  
25 ing to the known technique, the ROM 51 is tested while

allowing the user to control the input and output of data to/from the ROM 51 directly and externally.

However, where the user is allowed to control the data input and output to/from a ROM directly and externally, confidential information (e.g., microcode, secret keys and passwords), stored on the ROM, can be decoded easily by the third party such as hackers and crackers.

On the other hand, if a known built-in self-test (BIST) circuit is adopted, then the confidential information stored can have its security increased. However, to modify the contents of the confidential information, the BIST circuit itself, built in a semiconductor circuit, should be redesigned, thus considerably increasing the man-hour, the mask design cost and so on needed for the redesign process.

#### SUMMARY OF THE INVENTION

It is therefore an object of the present invention to make a ROM directly testable externally while ensuring a sufficient level of security for the confidential information stored on the ROM.

Specifically, a semiconductor integrated circuit according to the present invention includes: a ROM for storing confidential data thereon; a tester for testing the ROM; and means for storing redundancy check data that has been obtained by performing a predetermined calculation on the con-

fidential data. The tester includes a checker that performs the same type of calculation as the predetermined calculation on the confidential data that has been read out from the ROM. And a result of the calculation performed by the checker is compared to the redundancy check data stored on the storage means.

In the inventive integrated circuit, the tester includes a checker. The checker subjects the confidential data, which has been read out from the ROM, to the same type of calculation as the predetermined calculation that was carried out to produce the redundancy check data. Then, the result of the calculation performed by the checker is compared to the redundancy check data stored on the check data storage means. In this manner, the confidential data stored on the ROM can be error-checked without allowing the third party to read out the confidential data from the integrated circuit, and yet the ROM can be tested without decreasing the security level of the confidential data.

In one embodiment of the present invention, the storage means is preferably included in the ROM.

In this particular embodiment, the redundancy check data and the confidential data may be stored at mutually different addresses on the ROM.

In an alternative embodiment, the redundancy check data and the confidential data may be stored at the same address

on the ROM.

09867766-053101  
TOTAL 50.8880

An inventive method of testing a semiconductor integrated circuit, including a ROM for storing confidential data thereon, includes the steps of: a) storing redundancy check data, which has been obtained by performing a predetermined calculation on the confidential data, on redundancy check data storage means of the integrated circuit; b) reading out the confidential data from the ROM and performing the same type of calculation as the predetermined calculation on the confidential data read out; and c) reading out the redundancy check data from the storage means and then comparing a result of the calculation performed in the step b) to the redundancy check data read out.

#### BRIEF DESCRIPTION OF THE DRAWINGS

FIG. 1 is a block diagram illustrating a configuration for a semiconductor integrated circuit according to an embodiment of the present invention.

FIG. 2 is a timing diagram illustrating how the integrated circuit shown in FIG. 1 operates in test mode.

FIG. 3 illustrates an alternative data storage format for the ROM shown in FIG. 1.

FIG. 4 is a block diagram illustrating a configuration for a known ROM-built-in semiconductor integrated circuit with a tester.

## DESCRIPTION OF THE PREFERRED EMBODIMENTS

Hereinafter, preferred embodiments of the present invention will be described with reference to the accompanying drawings.

5        FIG. 1 illustrates a configuration for a semiconductor integrated circuit according to an embodiment of the present invention. The integrated circuit shown in FIG. 1 can test the ROM 10 without decreasing the security level of confidential information such as microcode, secret keys and passwords.

10        As shown in FIG. 1, a number  $(n+1)$  of confidential data words (0) through (n) are stored at respective low-order addresses of the ROM 10. Confidential CRC (cyclic redundancy check) codewords (0) through (n), which are equivalent to the "redundancy check data" as defined in the appended claims,  
15        have also been produced for the respective confidential data words (0) through (n) and are stored at respective high-order addresses of the ROM 10. In the example illustrated in FIG. 1, the ROM 10 includes the "redundancy check data storage means" as defined in the claims.

20        On the ROM 10, the confidential data words (0) through (n) are sequentially stored at the low-order addresses starting with the least significant bit (LSB) position thereof. On the other hand, the confidential CRC codewords (0) through (n) are sequentially stored at the high-order addresses starting  
25        with the most significant bit (MSB) position thereof. For ex-

ample, the confidential data word (0) is stored at the LSB position of the ROM 10, while the confidential CRC codeword (0), associated with this data word (0), is stored at the MSB position of the ROM 10. An addressing like this is suitably applicable to carrying out a complementary check on the ROM 10.

Also, in the circuit shown in FIG. 1, a tester is made up of selectors 21 and 22, address decoder (ADEC) 23, flip-flop (FF) 24, checker (CRC) 25 and comparator (COMP) 26. A logic circuit block (LOGIC) 30 for use in normal mode is further included in this circuit.

When a test signal TEST, received at respective input terminals S of the selectors 21 and 22, rises to H-level, the integrated circuit enters test mode. In test mode, each of the selectors 21 and 22 selects and outputs an input signal that the selector 21 or 22 has received at another input terminal A. Specifically, the selector 22 outputs a read signal READ to an address decoder included in the ROM 10. On the other hand, the selector 21 outputs an address signal ADD to the address decoder in the ROM 10 and to the ADEC 23 externally provided for the ROM 10. In response, the ADEC 23 decodes the address signal ADD, thereby controlling the CRC 25 and COMP 26. The CRC 25 performs a calculation on the confidential data words that have been read out from the ROM 10. The calculation carried out by the CRC 25 is of the same type as a

predetermined calculation that was performed to produce the confidential CRC codewords. Then, the CRC 25 outputs the result **OUT** of the calculation to the COMP 26. In response, the COMP 26 compares the output **OUT** of the CRC 25 to the confidential CRC codewords that have been read out from the ROM 10. In FIG. 1, a clock signal **CLK** is delivered as synchronous clock pulses to the respective circuit blocks 10, 24, 25 and 26.

In normal mode, the test signal **TEST** falls to the logical zero state (which will be herein referred to as "L-level"). Then, each of the selectors 21 and 22 selects an input signal that the selector 21 or 22 has received at another input terminal **B** thereof. That is to say, the input data, supplied from another block of the integrated circuit and then received through a pair of external input terminals **INA** and **INB**, are delivered to the ROM 10. The output **DO** of the ROM 10 is also supplied to the LOGIC 30 in the normal mode.

As described above, in the test mode, the test signal **TEST** rises to the H-level, when each of the selectors 21 and 22 selects an input signal that the selector 21 or 22 has received at the input terminal **A** thereof. That is to say, the input data, received through another pair of external terminals **IN1** and **IN2**, are supplied as the address and read signals **ADD** and **READ** to the ROM 10.

The input data, received through the external input ter-

09867766-053101  
TOP SECRET

minal **IN1**, is also delivered as the address signal **ADD** to the ADEC 23. If the input data received through the external input terminal **IN1** specifies one of the addresses (0) through (n) at which the confidential data words (0) through (n) are stored, then the ADEC 23 enables one **AOUT1** of its outputs, i.e., asserts the output **AOUT1** to H-level. One clock cycle after the output **AOUT1** was asserted, the CRC 25, which also received the output **DO** of the ROM 10, starts to operate. On the other hand, if the input data received through the external input terminal **IN1** specifies one of the addresses (n+1) through (2n+1) at which the confidential CRC codewords (n) through (0) are stored, then the ADEC 23 enables the other output **AOUT2**, i.e., asserts the output **AOUT2** to H-level. When the output **AOUT2** is asserted, the COMP 26 compares the result of the calculation performed by the CRC 25 (received as **IN1**) to the specified confidential CRC codeword read out from the ROM 10 (received as **IN2**). And if the result **IN1** of the calculation is found matching the CRC codeword **IN2**, then the COMP 26 asserts its output signal **RESULT**.

FIG. 2 illustrates how the integrated circuit shown in FIG. 1 operates in the test mode.

First, to make the integrated circuit enter the ROM test mode, the test signal **TEST** is asserted to H-level. Next, a signal, specifying the address (0) of the ROM 10 at which confidential data word (0) is stored, is input through the exter-





through the external input terminal **IN1**. At the same time, another H-level signal, enabling the read signal **READ** input to the ROM **10**, is input through the external input terminal **IN2**.

The ADEC **23** receives the signal specifying the address (2n+1), so outputs an L-level signal **AOUT1** to the FF **24** and an H-level signal **AOUT2** to the COMP **26**. In response, the COMP **26** compares the output **OUT** of the CRC **25** to the output **DO** of the ROM **10**, i.e., the confidential CRC codeword (0). And if the output **OUT** is found matching the output **DO**, then the COMP **26** asserts its output signal **RESULT** to H-level. Otherwise, the COMP **26** negates the signal **RESULT** to L-level.

Also, for one cycle time during the H-level period of the output **AOUT2**, a signal **COMPen** is asserted. When the signal **RESULT** is output, this signal **COMPen** is negated, thereby initializing the CRC **25**.

In this manner, the confidential data word (0) can be tested successfully.

Similar operations will be performed with the other pairs of addresses (1) and (2n), (2) and (2n-1), ... and (n) and (n+1) specified, and the signals **RESULT** are monitored externally. Based on these results, it is possible to determine whether or not any error has occurred at the ROM **10** due to some manufacturing problems, for example.

In the ROM **10** shown in FIG. 1, each confidential CRC codeword is stored at a different address from that of the as-

sociated confidential data word. Alternatively, each pair of confidential CRC codeword and confidential data word may be stored at the same address. For example, as shown in FIG. 3, the confidential CRC codewords may be mapped to respective bit positions that are in higher-order than the associated confidential data words.

Also, in the foregoing embodiment, the confidential CRC codewords are stored on the same ROM on which the confidential data words are stored. However, the confidential CRC codewords may also be stored on any other storage means (e.g., another ROM built in the semiconductor integrated circuit) provided separately from the ROM on which the confidential data words have been stored.

Moreover, according to the present invention, to modify the contents of confidential data, just the associated CRC codewords have to be changed and there is no need to change the configuration of the tester itself. Accordingly, the man-hour and mask design cost required can be cut down considerably.

Furthermore, not just the CRC code but any other type of data may be used for checking the confidential data. In the latter case, however, a checker that performs the same type of calculation as the predetermined calculation that was carried out to produce the check data should also be included in the tester.

Furthermore, in the foregoing illustrative embodiment, the present invention has been described as being applied to a synchronous ROM. However, the present invention is easily implementable as well even if an asynchronous ROM is used.

5 As is apparent from the foregoing description, the present invention makes it possible to test a ROM built in a semiconductor integrated circuit without decreasing the security level of confidential data stored on the ROM.